Power MOSFET, N-Channel, UniFET™ II

500 V, 4 A, 1.5 Ω

UniFET II MOSFET is ON Semiconductor's high voltage MOSFET family based on advanced planar stripe and DMOS technology. This advanced MOSFET family has the smallest on–state resistance among the planar MOSFET, and also provides superior switching performance and higher avalanche energy strength. In addition, internal gate–source ESD diode allows UniFET II MOSFET to withstand over 2 kV HBM surge stress. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.

Features

- $R_{DS(on)} = 1.38 \Omega$ (Typ.) @ $V_{GS} = 10 \text{ V}$, $I_D = 2 \text{ A}$
- Low Gate Charge (Typ. 9 nC)
- Low C_{rss} (Typ. 4 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- ESD Improved Capability
- These Devices are Pb-Free and are RoHS Compliant

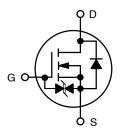
Applications

- LCD / LED TV
- Lighting
- Charger / Adapter



ON Semiconductor®

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CASE 369AR

ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 2 of this data sheet.

MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Value	Unit	
V _{DSS}	Drain-to-Source Voltage		500	V
V _{GSS}	Gate-to-Source Voltage		±25	V
I _D	Drain Current	Continuous (T _C = 25°C)	4	Α
		Continuous (T _C = 100°C)	2.4	
I _{DM}	Drain Current	Pulsed (Note 1)	16	Α
E _{AS}	Single Pulse Avalanche Energy (Note 2)		304	mJ
I _{AR}	Avalanche Current (Note 1)		4	Α
E _{AR}	Repetitive Avalanche Energy (Note 1)		6.2	mJ
dv/dt	Peak Diode Recovery (Note 3)		10	V/ns
P_{D}	Power Dissipation	T _C = 25°C	62	W
		Derate Above 25°C	0.5	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temperature for Soldering Purposes (1/8	300	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Repetitive Rating: Pulse width limited by maximum junction temperature.

2. $I_{AS} = 4 \text{ A}$, $V_{DD} = 50 \text{ V}$, L = 38 mH, $R_G = 25 \Omega$, starting $T_J = 25^{\circ}C$.

3. $I_{SD} \le 4 \text{ A}$, $di/dt \le 200 \text{ A}/\mu\text{s}$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	2.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	90	

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FDU5N50NZTU	FDU5N50NZ	IPAK	Tube	N/A	N/A	75 units

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
OFF CHARA	CTERISTICS					-
BV_DSS	Drain-to-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_J = 25^{\circ} C$	500			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.5		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 500 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 400 V, T _C = 125°C			10	
I _{GSS}	Gate-to-Body Leakage Current	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ
ON CHARAC	TERISTICS					
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	3.0		5.0	V
R _{DS(on)}	Static Drain-to-Source On Resistance	V _{GS} = 10 V, I _D = 2 A		1.38	1.5	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 20 V, I _D = 2 A		3.54		S
DYNAMIC CH	HARACTERISTICS					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz		330	440	pF
C _{oss}	Output Capacitance			50	70	1
C _{rss}	Reverse Transfer Capacitance			4	6	
Q _{g(tot)}	Total Gate Charge at 10 V	V _{DS} = 400 V, I _D = 4 A, V _{GS} = 10 V (Note 4)		9	12	nC
Q_{gs}	Gate-to-Source Gate Charge			2		
Q_{gd}	Gate-to-Drain "Miller" Charge			4		
SWITCHING	CHARACTERISTICS					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 250 V, I _D = 4 A,		12	35	ns
t _r	Turn-On Rise Time	V_{GS} = 10 V, R_G = 25 Ω (Note 4)		22	55	
t _{d(off)}	Turn-Off Delay Time			28	65	
t _f	Turn-Off Fall Time			21	50	
DRAIN-SOU	RCE DIODE CHARACTERISTICS			_		
IS	Maximum Continuous Drain to Source Dioc	le Forward Current			4	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current				16	1
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 4 A			1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{SD} = 4 \text{ A,}$ $dI_F/dt = 100 \text{ A/}\mu\text{s}$		210		ns
Q _{rr}	Reverse Recovery Charge			1.1		μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of Operating Temperature Typical Characteristics.

TYPICAL CHARACTERISTICS

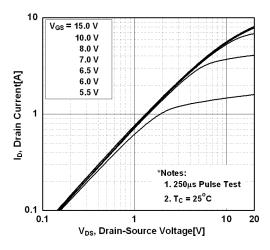


Figure 1. On-Region Characteristics

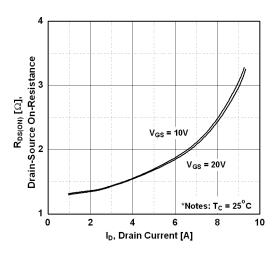


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

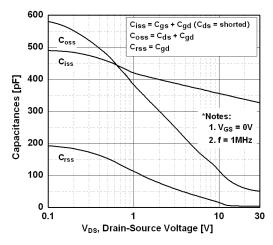


Figure 5. Capacitance Characteristics

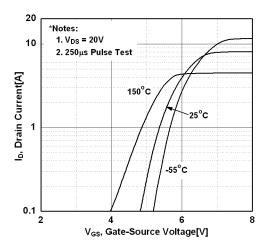


Figure 2. Transfer Characteristics

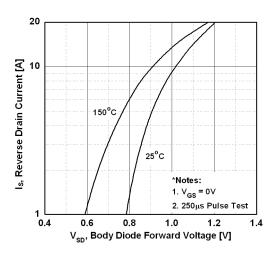


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

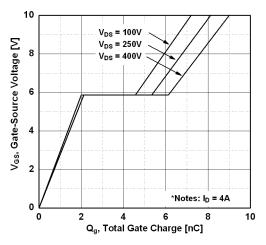


Figure 6. Gate Charge Characteristics

TYPICAL CHARACTERISTICS

3.0

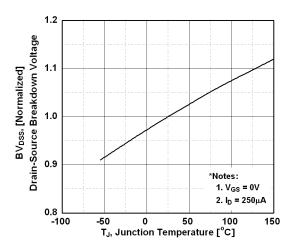
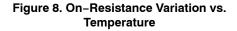
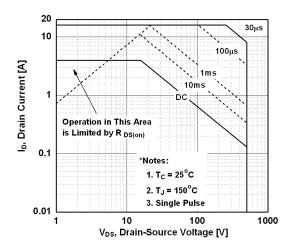


Figure 7. Breakdown Voltage Variation vs. Temperature





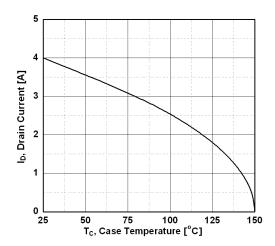


Figure 9. Maximum Safe Operating Area vs.

Case Temperature

Figure 10. Maximum Drain Current

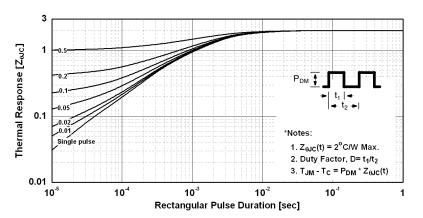


Figure 11. Transient Thermal Response Curve

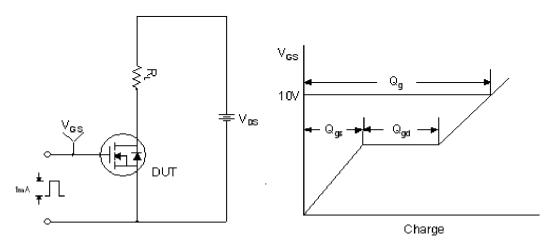


Figure 12. Gate Charge Test Circuit & Waveform

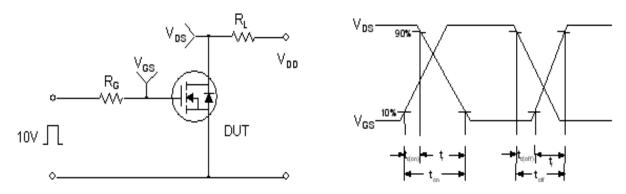


Figure 13. Resistive Switching Test Circuit & Waveforms

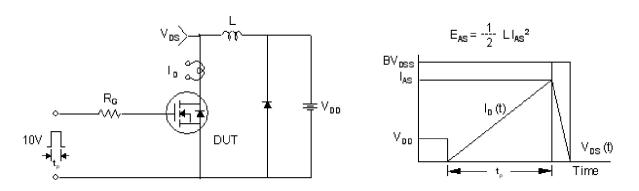
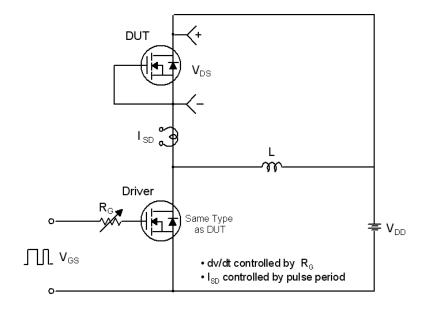


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



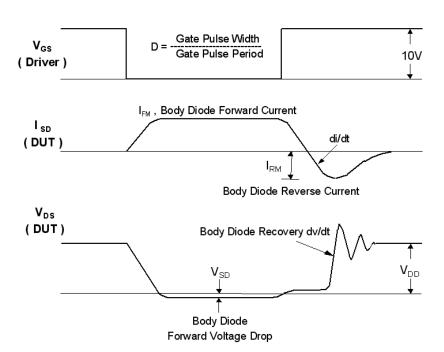
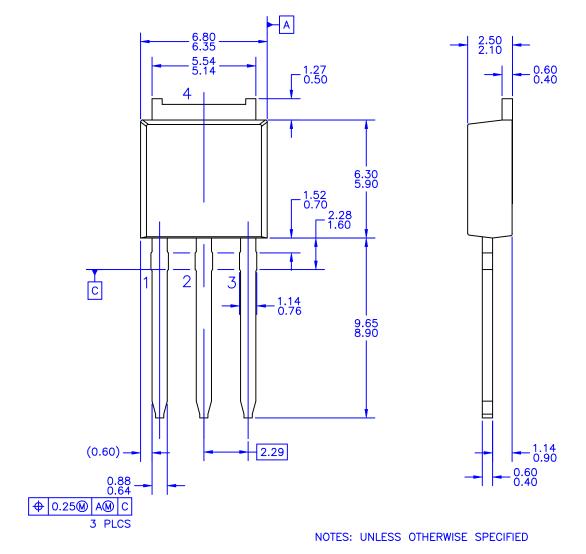


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

DPAK3 (IPAK) CASE 369AR ISSUE O

DATE 30 SEP 2016





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